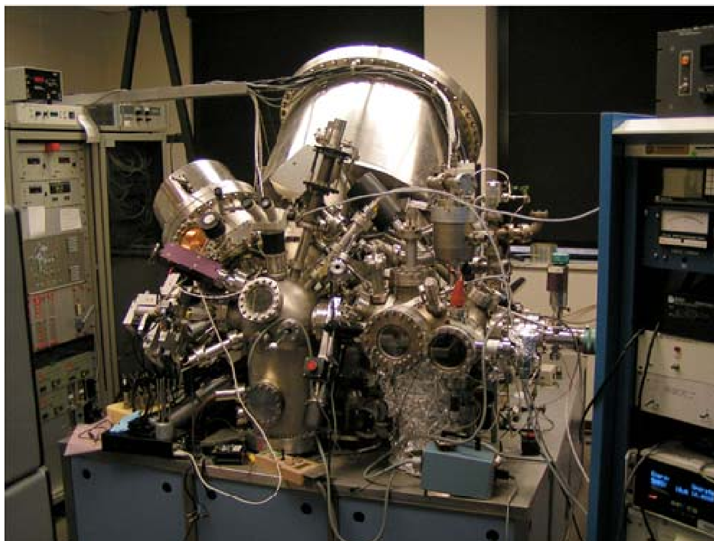
A Unique Surface Analysis Symposium - Cutting Edge Surface Analysis Instrumentation at Lehigh University



ION-TOF Qtac 100 HS-LEIS

Scienta ESCA-300 HR-XPS

Lehigh University is now home to two unique surface analysis instruments that are ***the only such advanced surface characterization instruments in North America***: ION-TOF Qtac 100 High Sensitivity-Low Energy Ion Scattering (HS-LEIS) and Scienta ESCA-300 High Resolution-X-ray Photoelectron Spectroscopy (HS-XPS) capable of 02.-0.3 nm and 1-3 nm depth analysis, respectively. Both spectrometers are also equipped with *in situ* pretreatment chambers. The just installed HS-LEIS system utilizes a unique double toroidal electrostatic energy analyzer that provides 3,000x higher sensitivity than conventional ion scattering spectrometers. The HR-XPS system employs a high X-ray flux to yield high resolution, rapid analysis and enhanced detection level that approaches the capabilities of a synchrotron source. Our symposium will highlight and discuss their advanced capabilities with lectures from Dr. Hidde Brongersma (inventor of the Qtac HS-LEIS), Professors Wachs and Jain, Dr. Miller, posters to demonstrate applications as well as a laboratory tour.

March 23, 2011
1:00 PM—5:00 PM

Lehigh University

Whitaker Auditorium (Bldg. 5)
Bethlehem, PA

Free Attendance (preregistration required)

For more details or to register for the symposium visit:
www.Lehigh.edu/operando/symposium.html